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M	AC	5,206,925	4/27/93	Nakazawa et al.	385	142				
MX M	AD	5,252,194	10/12/93	Demaray et al.	204	298.2				
	AE	5,303,319	4/12/94	Ford et al.	385	131		·		
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VM	AG	5,427,669	6/27/95	Drummond	204	298.2				
44.0	AH	5,475,528	12/12/95	LaBorde	359	341				
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1///	AK	5,563,979	10/8/96	Bruce et al.	385	142				
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	AB	5,603,816	2/18/97	Demaray et al.	204	298.07		
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	AD	5,718,813	2/17/98	Drummond et al.	204	192.12		T I
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